

# MCR8DCM, MCR8DCN





#### **Description**

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

#### **Features**

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and **Holding Characteristics**
- Available in Two Package Styles Surface Mount Lead Form - Case 369C
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Human

Body Model, 3B > 8000 V Machine Model, C > 400 V

• Pb-Free Packages are Available

# **Pin Out**



#### **Functional Diagram**



# **Additional Information**







Resources



Samples



# **Maximum Ratings** $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

Rating		Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (- 40 to 1125°C, Sine Wave, 50 to 60 Hz, Gate Open)	MCR8DCM MCR8DCN	V <sub>DRM</sub> ,	600 800	V
On-State RMS Current (180°Conduction Angles; T <sub>C</sub> = 105°C)		I <sub>T (RMS)</sub>	8.0	А
Average On-State Current (180° Conduction Angles; T <sub>C</sub> = 105°C)		I <sub>T(AV)</sub>	5.1	А
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, TJ = 110°C)		I <sub>TSM</sub>	80	А
Circuit Fusing Consideration (t = 8.3 ms)		l²t	26	A²sec
Forward Peak Gate Power (Pulse Width ≤ 10 µsec, T <sub>c</sub> = 105°C)		P <sub>GM</sub>	5.0	W
Forward Average Gate Power (t = 8.3 msec, T <sub>c</sub> = 105°C)		P <sub>GM (AV)</sub>	0.5	W
Forward Peak Gate Current (Pulse Width ≤ 1.0 µsec, T <sub>c</sub> = 105°C)		I <sub>GM</sub>	2.0	А
Operating Junction Temperature Range		T <sub>J</sub>	-40 to 125	°C
Storage Temperature Range		T <sub>stg</sub>	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

#### **Thermal Characteristics**

Rating	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R <sub>eJC</sub>	2.2	
Thermal Resistance, Junction-to-Ambient	R <sub>eJA</sub>	88	°C/W
Thermal Resistance, Junction-to-Ambient (Note 2)	R <sub>eJA</sub>	80	
Maximum Device Temperature for Soldering Purposes (Note 3)	T <sub>L</sub>	260	°C

#### **Electrical Characteristics** - **OFF** (T<sub>1</sub> = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Forward or Reverse Blocking Current (Note 3)	$T_J = 25^{\circ}C$	I <sub>DRM</sub> ,	-	-	0.01	m ^
$(V_{AK} = Rated V_{DRM} or V_{RRM}, R_{GK} = 1.0 k\Omega$	T <sub>J</sub> = 125°C	I <sub>RRM</sub>	-	-	5.0	mA mA

#### Electrical Characteristics - ON (T<sub>1</sub> = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak On-State Voltage (Note 4) (I <sub>TM</sub> = 16 A)		$V_{TM}$	_	1.4	1.8	V
Gate Trigger Current (Continuous dc) (Note 5) (V <sub>AK</sub> = 12 Vdc, R <sub>L</sub> = 100 $\Omega$ )	$(T_J = 25^{\circ}C)$ $(T_J = -40^{\circ}C)$	I <sub>GT</sub>	2.0	7.0 –	15 30	μА
Gate Trigger Voltage (Continuous dc) ( $V_D = 12 \text{ V}, R_L = 100 \Omega$ ) ( $V_D = 12 \text{ V}, R_L = 100 \Omega$ ) (Note 5)	$(T_J = 25^{\circ}C)$ $(T_J = -40^{\circ}C)$ $(T_J = 125^{\circ}C)$	$V_{GT}$	0.5 - 0.2	0.65 - -	1.0 2.0 –	V
Holding Current ( $V_D = 12 \text{ V}$ , Initiating Current = 200 mA, $R_{GK} = 1 \text{ k}\Omega$ )	$(T_J = 25^{\circ}C)$ $(T_J = -40^{\circ}C)$	I <sub>H</sub>	4.0	22	30 60	mA
Latching Current (V <sub>D</sub> = 12 V, IG = 2.0 mA, R <sub>GK</sub> = $1 \text{ k}\Omega$ )	$(T_J = 25^{\circ}C)$ $(T_J = -40^{\circ}C)$	I <sub>L</sub>	4.0	22 -	30 60	mA

#### **Dynamic Characteristics**

Characteristic	Symbol	Min	Тур	Max	Unit
Critical Rate of Rise of Off–State Voltage $(V_{AK} = Rated V_{DRM'} Exponential Waveform, Gate Open, T_J = 125°C)$	dv/dt	50	200	-	V/µs
Critical Rate of Rise of On-State Current (IPK = 50 A, Pw = 40 sec, diG/dt = 1 A/sec, Igt = 50 mA	di/dt	-	-	50	A/ms

<sup>2.</sup> Surface mounted on minimum recommended pad size.

V<sub>DRM</sub> and V<sub>RRM</sub> for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

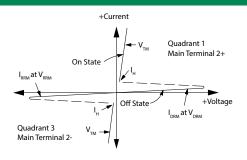
<sup>3 1/8&</sup>quot; from case for 10 seconds.

<sup>4.</sup> Pulse Test; Pulse Width  $\leq$  2.0 msec, Duty Cycle  $\leq$  2%.



# **Voltage Current Characteristic of SCR**

Symbol	Parameter
$V_{DRM}$	Peak Repetitive Forward Off State Voltage
I <sub>DRM</sub>	Peak Forward Blocking Current
V <sub>RRM</sub>	Peak Repetitive Reverse Off State Voltage
I <sub>RRM</sub>	Peak Reverse Blocking Current
V <sub>TM</sub>	Maximum On State Voltage
I <sub>H</sub>	Holding Current



**Figure 1. Average Current Derating** 

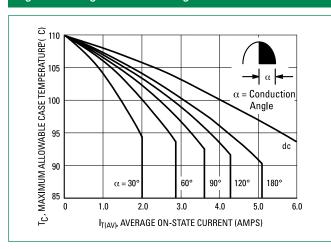


Figure 2. On–State Power Dissipation

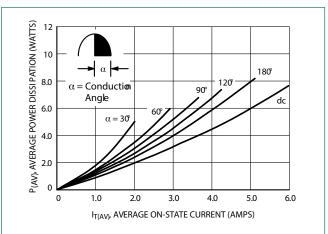


Figure 3. On-State Characteristics

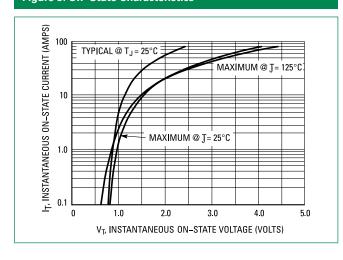


Figure 4. Transient Thermal Response

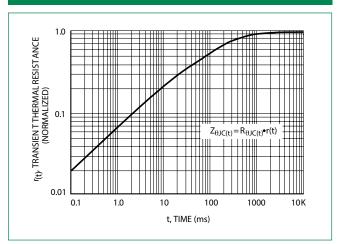




Figure 5. Typical Gate Trigger Current vs Junction Temperature

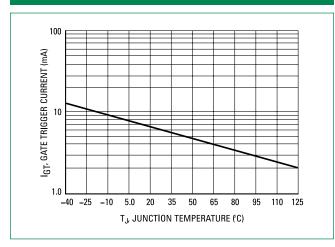


Figure 6. Typical Gate Trigger Voltage vs Junction Temperature

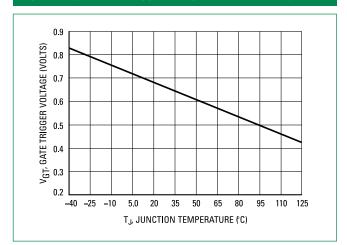


Figure 7. Typical Holding Current vs Junction Temperature

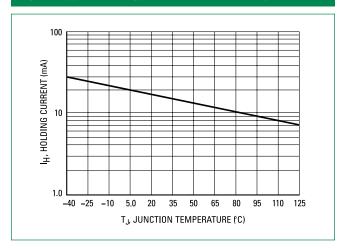


Figure 8. Typical Latching Current vs Junction Temperature

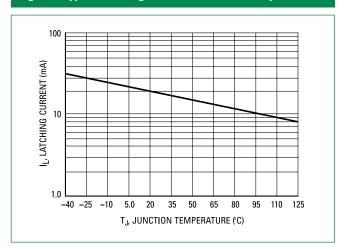
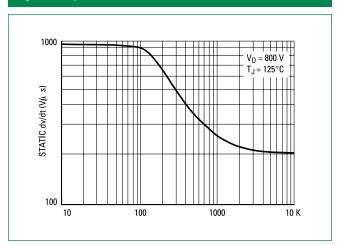
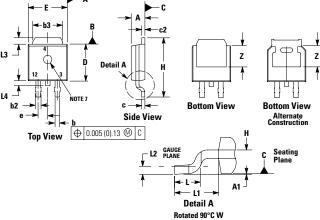


Figure 9. Exponential Static dv/dt vs Gate-Cathode Resistance





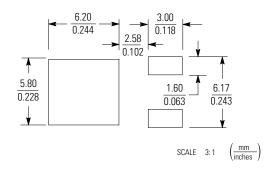
**Dimensions** 



D:	Inches		Millin	neters
Dim	Min	Max	Min	Max
Α	0.087	0.094	2.20	2.40
A1	0.000	0.005	0.00	0.12
b	0.022	0.030	0.55	0.75
b2	0.026	0.033	0.65	0.85
b3	0.209	0.217	5.30	5.50
С	0.019	0.023	0.49	0.59
c2	0.019	0.023	0.49	0.59
D	0.213	0.224	5.40	5.70
E	0.252	0.260	6.40	6.60
е	0.0	91	2.30	
Н	0.374	0.406	9.50	10.30
L	0.058	0.070	1.47	1.78
L1	0.1	114	2.9	90
L2	0.019	0.023	0.49	0.59
L3	0.053	0.065	1.35	1.65
L4	0.028	0.039	0.70	1.00
Z	0.154	-	3.90	-

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: INCH.

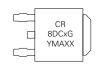
### **Soldering Footprint**



#### **Part Marking System**



DPAK-3 Case 369C Style 4



=Year Μ =Month =Assembly Site Α AKA =Diode Polarity

Pin Assignment			
1	Cathode		
2	Anode		
3	Gate		
4	Anode		

# **Ordering Information**

Device	Package	Shipping
MCR8DSMT4	DPAK	
MCR8DCMT4G	DPAK (Pb-Free)	2500 /
MCR8DCNT4	DPAK	Tape & Reel
MCR8DCNT4G	DPAK (Pb-Free)	

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